

## 60V N-Channel MOSFET

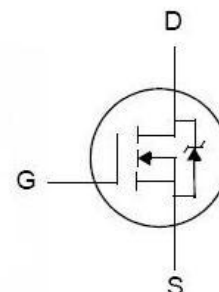
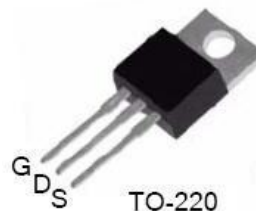
### General Features

- Low ON Resistance
- Low Gate Charge (typical 20nC)
- Fast Switching
- 100% Avalanche Tested
- Optimized Bvdss Capability
- RoHS Compliant
- Halogen-free available

$BV_{DSS}$	$R_{DS(ON)}$ (Max.)	$I_D$
60V	18mΩ	68A

### Applications

- Power Supply
- DC-DC Converters



### Ordering Information

Part Number	Package	Marking
FTP18N06N	TO-220	FTP18N06N

### Absolute Maximum Ratings

 $T_C=25^{\circ}\text{C}$  unless otherwise specified

Symbol	Parameter	FTP18N06N	Unit
$V_{DSS}$	Drain-to-Source Voltage <sup>[1]</sup>	60	V
$I_D$	Continuous Drain Current	68	A
$I_{DM}$	Pulsed Drain Current, $V_{GS}@10V$ <sup>[2]</sup>	272	
$P_D$	Power Dissipation	115	W
	Derating Factor above 25°C	0.77	W/°C
$V_{GS}$	Gate-to-Source Voltage	±20	V
$E_{AS}$	Single Pulse Avalanche Energy $L=11.9$ $I_D=5.5A$	360	mJ
dv/dt	Peak Diode Recovery dv/dt <sup>[3]</sup>	4.5	V/ns
$T_L$	Soldering Temperature	300	°C
	Distance of 1.6mm from case for 10 seconds		
$T_J$ and $T_{STG}$	Operating and Storage Temperature Range	-55 to 175	

\*Drain Current limited by Maximum Junction Temperature.

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" may cause permanent damage to the device.

### Thermal Characteristics

Symbol	Parameter	FTP18N06N	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	1.3	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62	

## Electrical Characteristics

### OFF Characteristics

 $T_J = 25^\circ\text{C}$  unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
$BV_{DSS}$	Drain-to-Source Breakdown Voltage	60	--	--	V	$V_{GS}=0V, I_D=250\mu A$
$I_{DSS}$	Drain-to-Source Leakage Current	--	--	1.0	$\mu A$	$V_{DS}=48V, V_{GS}=0V$
		--	--	100		$V_{DS}=48V, V_{GS}=0V, T_J=125^\circ C$
$I_{GSS}$	Gate-to-Source Leakage Current	--	--	100	nA	$V_{GS}=+20V$
		--	--	-100		$V_{GS}=-20V$

### ON Characteristics

 $T_J = 25^\circ\text{C}$  unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
$R_{DS(ON)}$	Static Drain-to-Source On-Resistance	--	12.5	18	m $\Omega$	$V_{GS}=10V, I_D=30A^{[4]}$
$V_{GS(TH)}$	Gate Threshold Voltage	2.0	--	4.0	V	$V_{DS} = V_{GS}, I_D=250\mu A$
gfs	Forward Transconductance	--	--	--	S	$V_{DS} = 30V, I_D=30A^{[4]}$

### Dynamic Characteristics

Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
$C_{ISS}$	Input Capacitance	--	1008	--	Pf	$V_{GS}=0V$ $V_{DS}=30V$ $f=1.0MHz$
$C_{OSS}$	Output Capacitance	--	158	--		
$C_{RSS}$	Reverse Transfer Capacitance	--	67	--		
$Q_G$	Total Gate Charge	--	20	--	nC	$V_{DD}=30V$ $I_D=68A$ $V_{GS}=10V$
$Q_{GS}$	Gate-to-Source Charge	--	7.0	--		
$Q_{GD}$	Gate-to-Drain (Miller) Charge	--	6.8	--		

### Resistive Switching Characteristics

Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
$t_{d(ON)}$	Turn-on Delay Time	--	8.7	--	Ns	$V_{DD}=30V$ $I_D=68A$ $V_{GS}=10V$ $R_G=2.5\Omega$
$t_{rise}$	Rise Time	--	45.1	--		
$t_{d(OFF)}$	Turn-off Delay Time	--	25.6	--		
$t_{fall}$	Fall Time	--	6.8	--		

**Source-Drain Diode Characteristics**
 $T_J=25^{\circ}\text{C}$  unless otherwise specified

Symbol	Parameter	Min	Typ.	Max.	Units	Test Conditions
$I_{SD}$	Continuous Source Current (Body Diode)	--	--	68	A	Integral P-N diode in MOSFET
$I_{SM}$	Maximum Pulsed Current (Body Diode)	--	--	272	A	
$V_{SD}$	Diode Forward Voltage	--	--	1.2	V	$I_S=30\text{A}$ , $V_{GS}=0\text{V}$
$t_{rr}$	Reverse Recovery Time	--	--	--	ns	$V_{GS}=0\text{V}$ $I_F=68\text{A}$ , $di/dt=100\text{A}/\mu\text{s}$
$Q_{rr}$	Reverse Recovery Charge	--	--	--	nC	

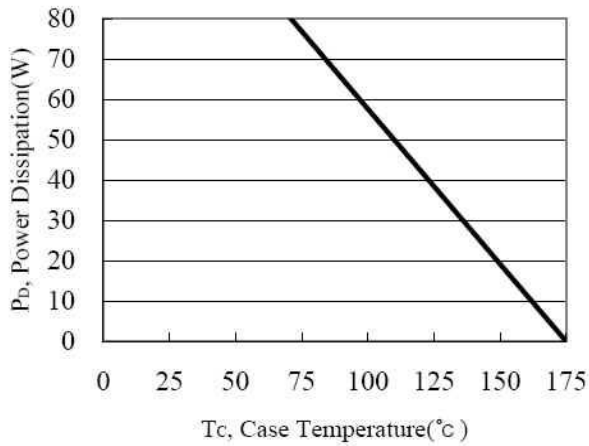
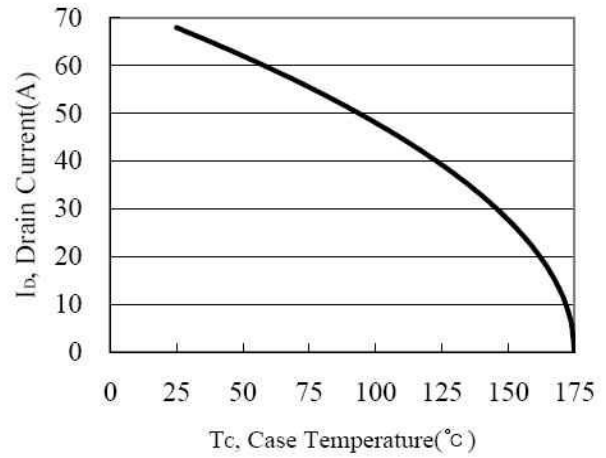
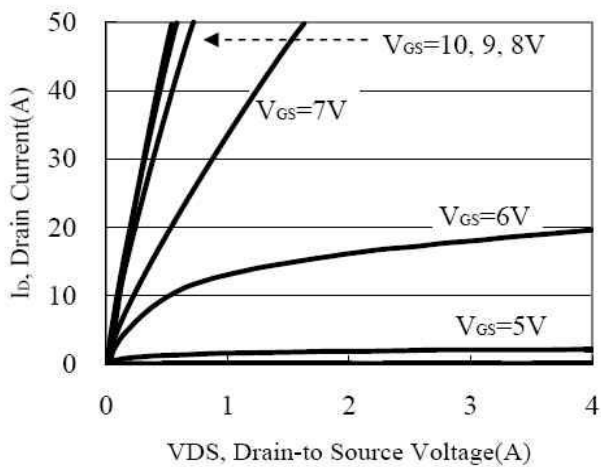
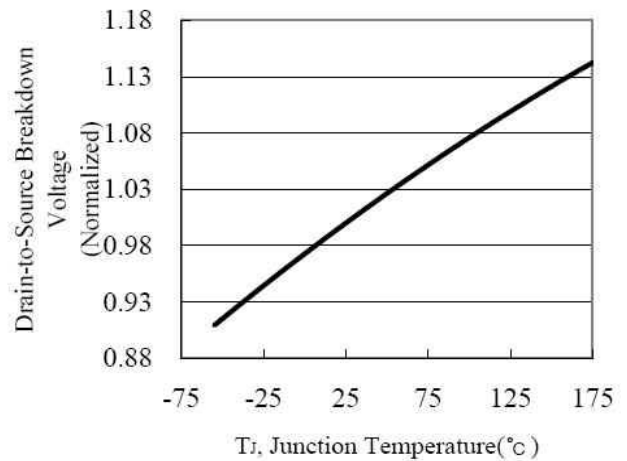
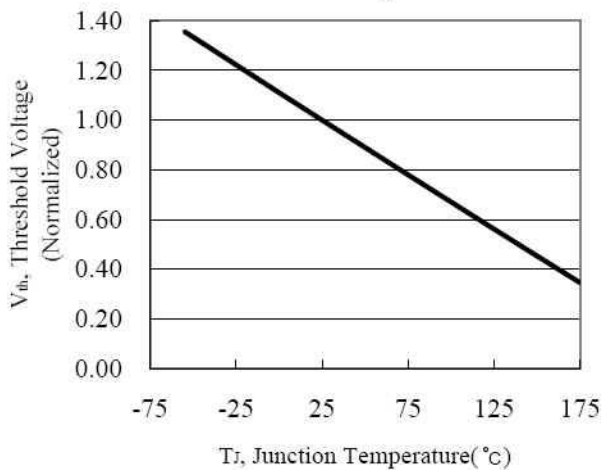
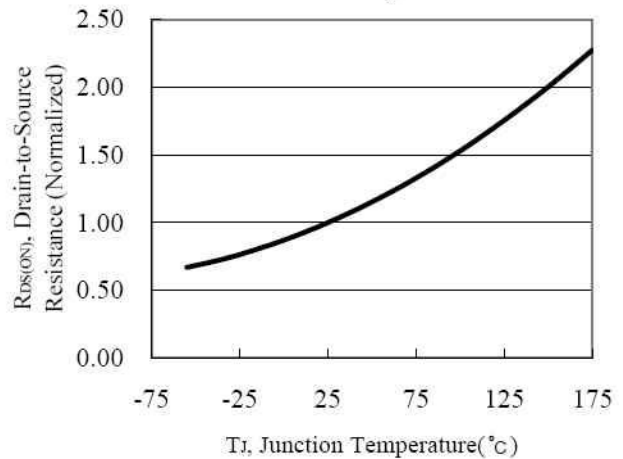
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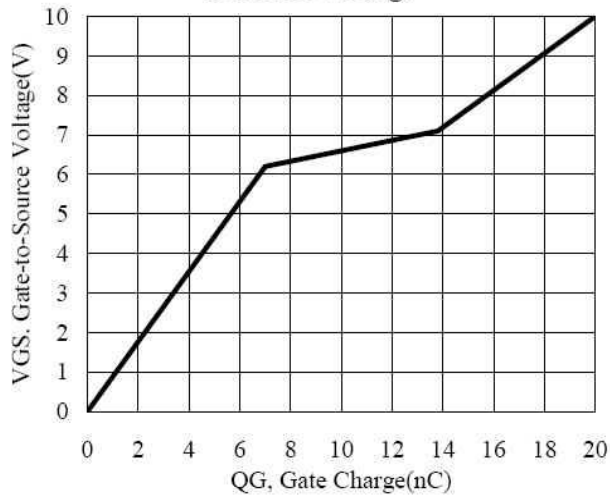
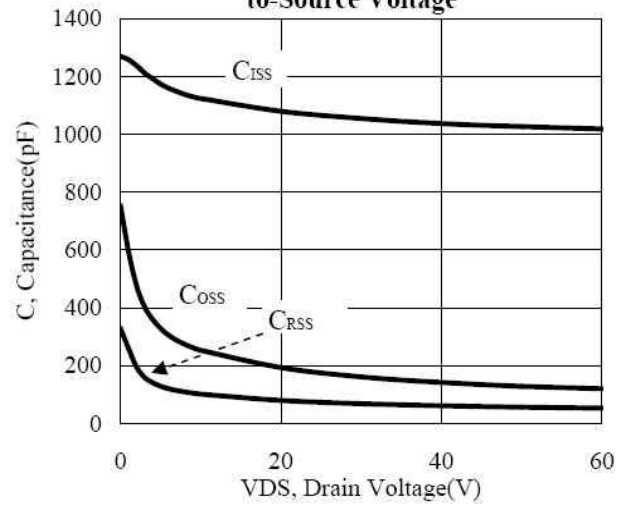
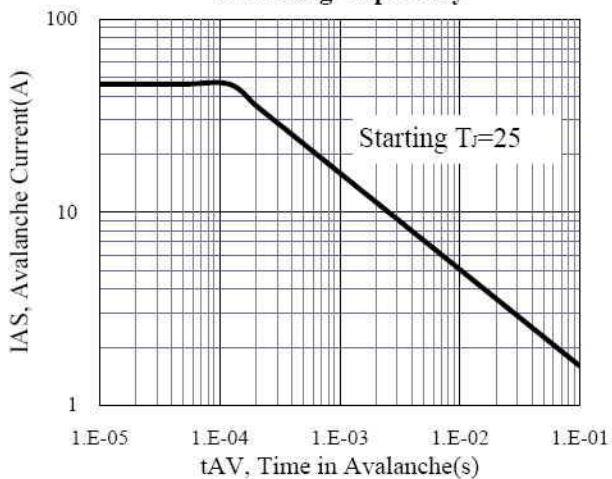
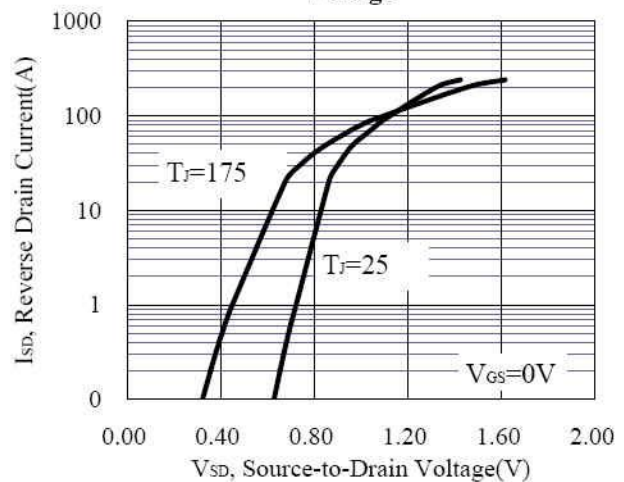
[1]  $T_J=+25^{\circ}\text{C}$  to  $+175^{\circ}\text{C}$

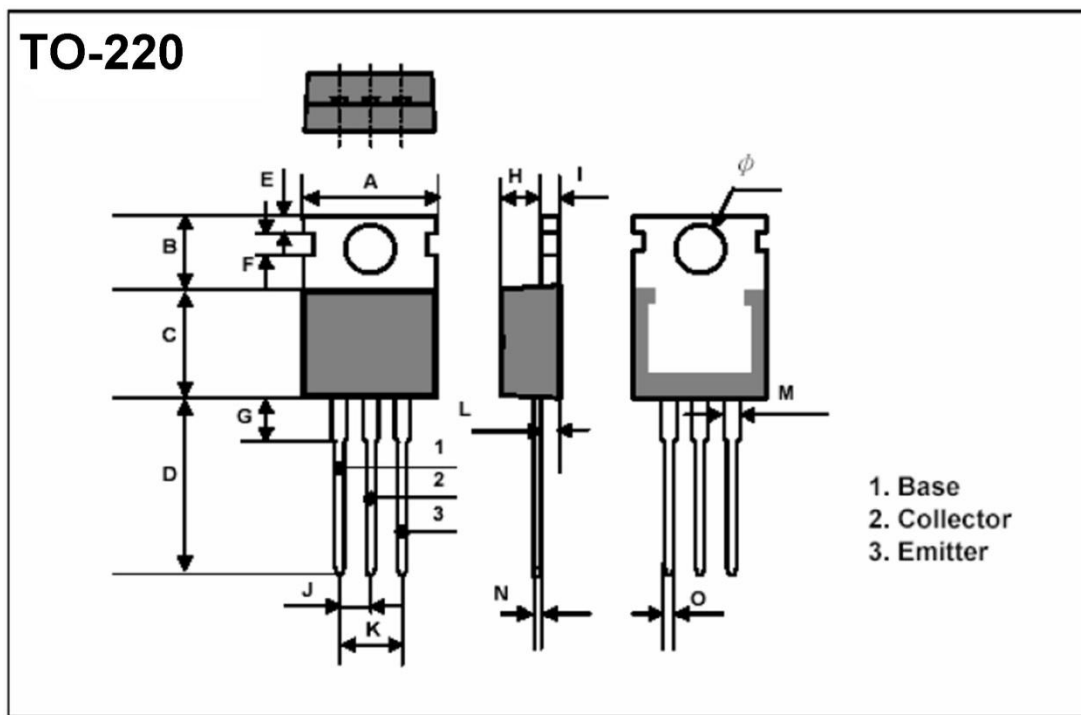
[2] Repetitive rating, pulse width limited by maximum junction temperature.

[3]  $I_{SD}=68\text{A}$ ,  $di/dt \leq 100\text{A}/\mu\text{s}$ ,  $V_{DD} \leq BV_{DSS}$ ,  $T_J=+175^{\circ}\text{C}$

[4] Pulse width  $\leq 380\mu\text{s}$ ; duty cycle  $\leq 2\%$ .

**Figure 1. Maximum Power Dissipation V.S Case Temperature**

**Figure 2. Maximum Continuous Drain Current V.S Case Temperature**

**Figure 3. Typical Output Characteristics**

**Figure 4. Breakdown Voltage V.S Junction Temperature**

**Figure 5. Threshold Voltage V.S Junction Temperature**

**Figure 6. Drain-to-Source Resistance V.S Junction Temperature**


**Figure 7. Typical Gate Charge vs. Gate-to-Source Voltage**

**Figure 8. Typical Capacitance vs. Drain-to-Source Voltage**

**Figure 9. Unclamped Inductive Switching Capability**

**Figure 10. Source-Drain Diode Forward Voltage**


**Package Dimensions**


symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	9.7	10.1	0.382	0.398
B	6.3	6.7	0.248	0.264
C	9.0	9.47	0.354	0.373
D	12.8	13.3	0.504	0.524
E	1.2	1.4	0.047	0.055
F	1.7TYP		0.067TYP	
G	2.65TYP		0.104TYP	
H	3.0	3.4	0.118	0.134
I	1.25	1.4	0.049	0.055
J	2.4	2.7	0.094	0.106
K	5.0	5.15	0.197	0.203
L	2.2	2.6	0.087	0.102
M	1.25	1.45	0.049	0.057
N	0.45	0.6	0.018	0.024
O	0.7	0.9	0.027	0.035
φ	3.6		0.142	



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